

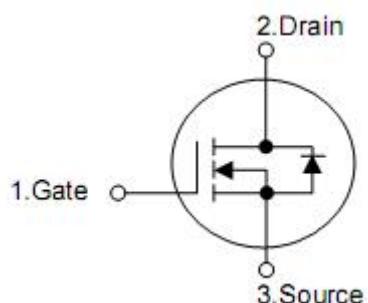
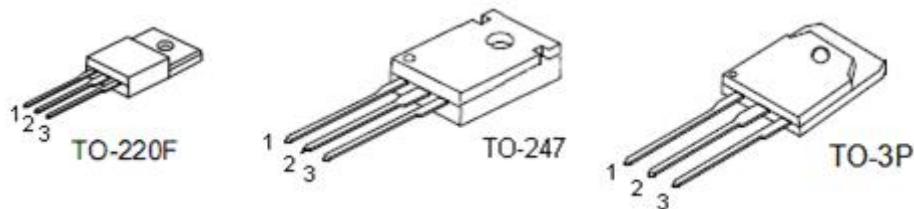
## 1. Description

The KIA20N50H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as high efficiency switched mode power supplies, active power factor correction.

## 2. Features

- $R_{DS(on)}=0.21\Omega$  @  $V_{GS}=10V$
- Low gate charge ( typical 70nC)
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source

## 4. Absolute maximum ratings

Parameter		Symbol	Ratings			Units
			TO220F	TO247	TO3P	
Drain-source voltage		V <sub>DSS</sub>	500			V
Gate-source voltage		V <sub>GSS</sub>	±30			V
Drain current continuous	T <sub>C</sub> =25°C	I <sub>D</sub>	20.0			A
	T <sub>C</sub> =100°C		13*	13.0	13.0	A
Drain current pulsed (note1)		I <sub>DP</sub>	80*	80	80	A
Avalanche energy	Repetitive (note1)	E <sub>AR</sub>	3.8	28	28	mJ
	Single pulse (note2)	E <sub>AS</sub>	1110			mJ
Peak diode recovery dv/dt (note 3)		dv/dt	4.5			V/ns
Total power dissipation	T <sub>C</sub> =25°C	P <sub>D</sub>	41.5	280	280	W
	derate above 25°C		0.33	2.3	2.3	W/°C
Junction temperature		T <sub>J</sub>	+150			°C
Storage temperature		T <sub>STG</sub>	-55~+150			°C

\*Drain current limited by maximum junction temperature.

## 5. Thermal characteristics

Parameter	Symbol	Ratings			Units
		TO-220F	TO-247	TO-3P	
Thermal resistance, junction-ambient	R <sub>thJA</sub>	62.5	40	40	°C/W
Thermal resistance, case-to-sink typ.	R <sub>thCS</sub>	--	0.24	0.24	
Thermal resistance, Junction-case	R <sub>thJC</sub>	3.0	0.45	0.45	

## 6. Electrical characteristics

( $T_J=25^\circ\text{C}$ ,unless otherwise specified)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Off characteristics</b>						
Drain-source breakdown voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	500	-	-	V
Zero gate voltage drain current	$I_{\text{DS}}^{\text{SS}}$	$V_{\text{DS}}=500\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{\text{DS}}=400\text{V}, T_c=125^\circ\text{C}$	-	-	10	$\mu\text{A}$
Gate-body leakage current	$I_{\text{GSS}}$	$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	100	nA
		$V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	-100	nA
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$I_{\text{D}}=250\mu\text{A}$	-	0.5	-	$\text{V}/^\circ\text{C}$
<b>On characteristics</b>						
Gate threshold voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Static drain-source on-resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=10.0\text{A}$	-	0.21	0.26	$\Omega$
<b>Dynamic characteristics</b>						
Input capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	2700	-	pF
Output capacitance	$C_{\text{oss}}$		-	400	-	pF
Reverse transfer capacitance	$C_{\text{rss}}$		-	40	-	pF
<b>Switching characteristics</b>						
Turn-on delay time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=250\text{V}, I_{\text{D}}=20.0\text{A}, R_{\text{G}}=25\Omega$ (note4,5)	-	100	-	ns
Rise time	$t_r$		-	400	-	ns
Turn-off delay time	$t_{\text{d}(\text{off})}$		-	100	-	ns
Fall time	$t_f$		-	100	-	ns
Total gate charge	$Q_g$	$V_{\text{DS}}=400\text{V}, I_{\text{D}}=20.0\text{A}, V_{\text{GS}}=10\text{V}$ (note4,5)	-	70	-	nC
Gate-source charge	$Q_{\text{gs}}$		-	18	-	nC
Gate-drain charge	$Q_{\text{gd}}$		-	35	-	nC
<b>Drain-source diode characteristics</b>						
Drain-source diode forward voltage	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=20.0\text{A}$	-	-	1.5	V
Continuous drain-source current	$I_{\text{SD}}$		-	-	20.0	A
Pulsed drain-source current	$I_{\text{SM}}$		-	-	80.0	A
Reverse recovery time	$t_{\text{rr}}$	$I_{\text{SD}}=20.0\text{A}$ $dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$ (note4)	-	500	-	ns
Reverse recovery charge	$Q_{\text{rr}}$		-	7.2	-	$\mu\text{C}$

Note:1Repetitive rating:pulse width limited by maximum junction temperature

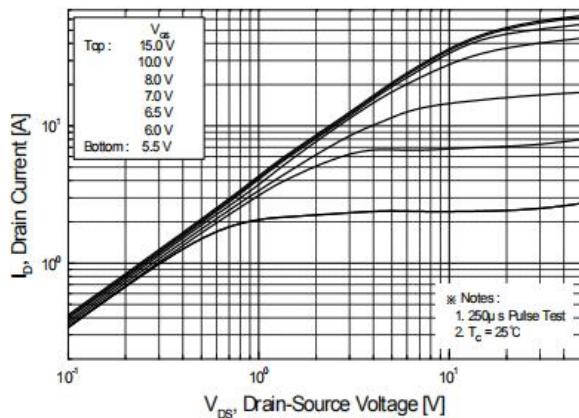
2. $L=5.0\text{mH}, I_{\text{AS}}=20.0\text{A}, V_{\text{DD}}=50\text{V}, R_{\text{G}}=25\Omega$ ,staring  $T_J=25^\circ\text{C}$

3. $I_{\text{SD}}\leq 20.0\text{A}, dI/dt\leq 200\text{A}/\mu\text{s}, V_{\text{DD}}\leq \text{BV}_{\text{DSS}}$ ,staring  $T_J=25^\circ\text{C}$

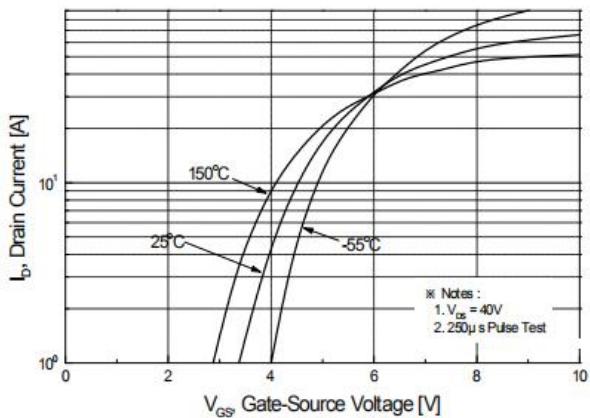
4.Pulse test:pulse width $\leq 300\mu\text{s}$ ,duty cycle $\leq 2\%$

5.Essentially independent of operating temperature

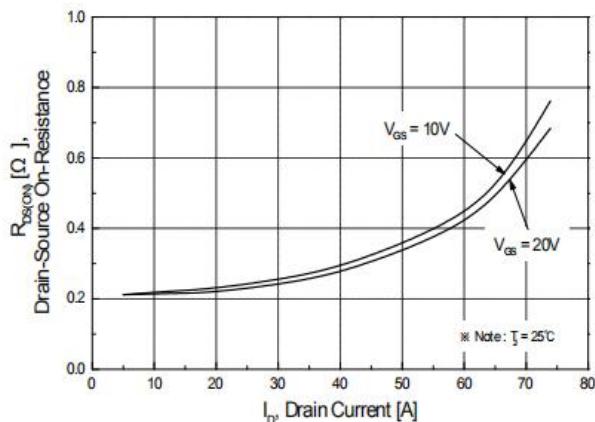
## 7. Test circuits and waveforms



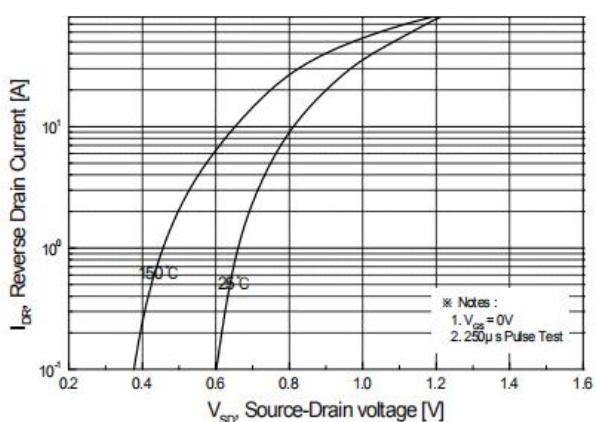
**Figure 1. On-Region Characteristics**



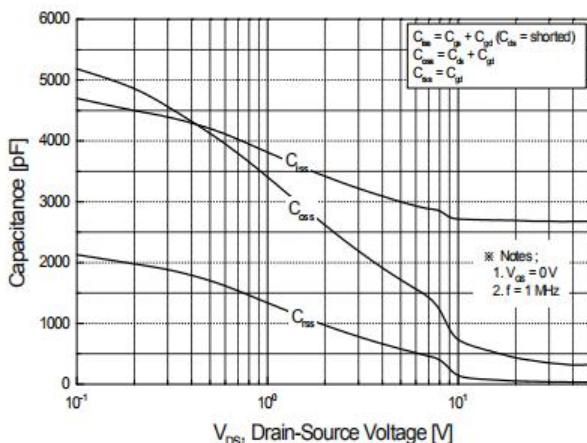
**Figure 2. Transfer Characteristics**



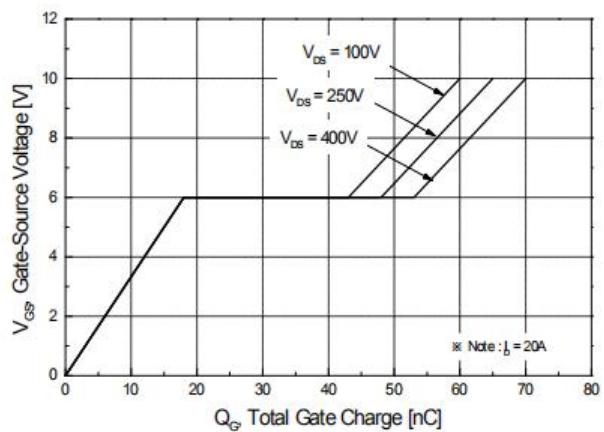
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



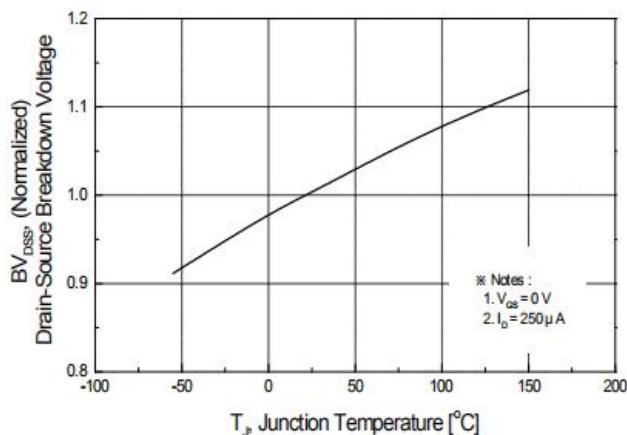
**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**



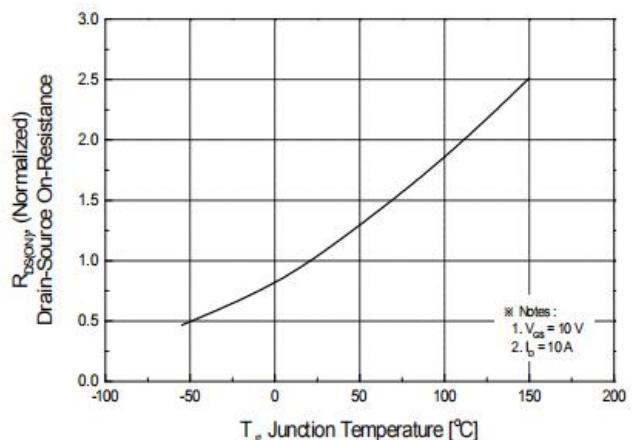
**Figure 5. Capacitance Characteristics**



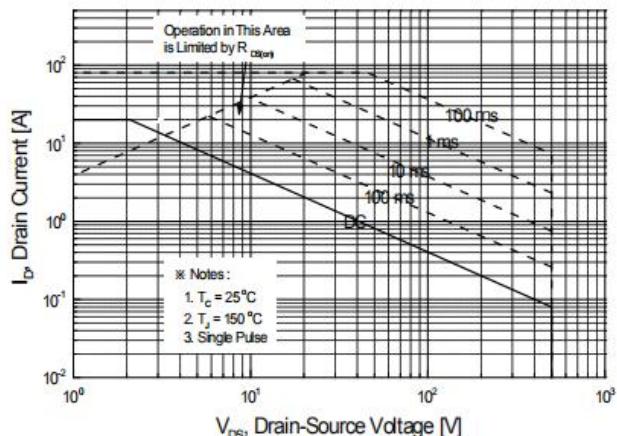
**Figure 6. Gate Charge Characteristics**



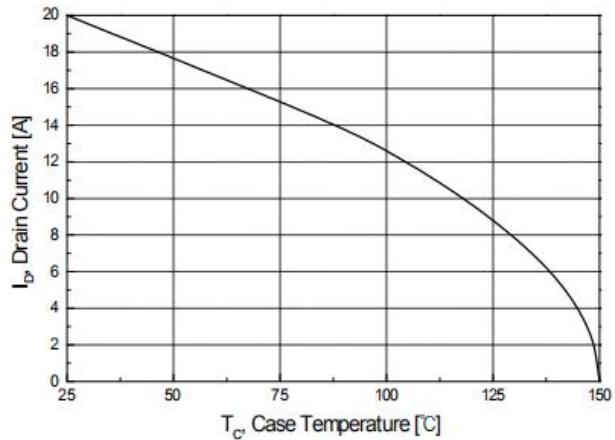
**Figure 7. Breakdown Voltage Variation vs Temperature**



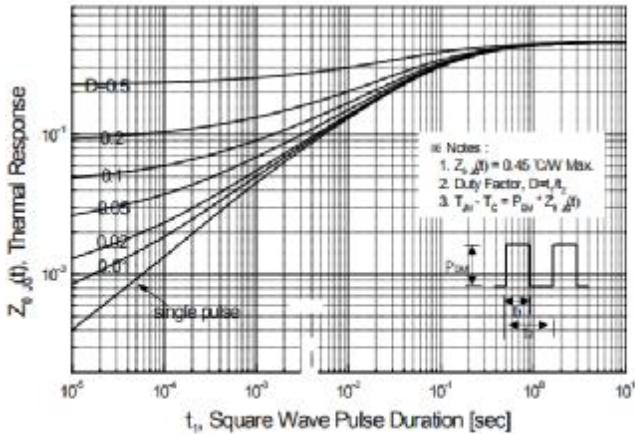
**Figure 8. On-Resistance Variation vs Temperature**



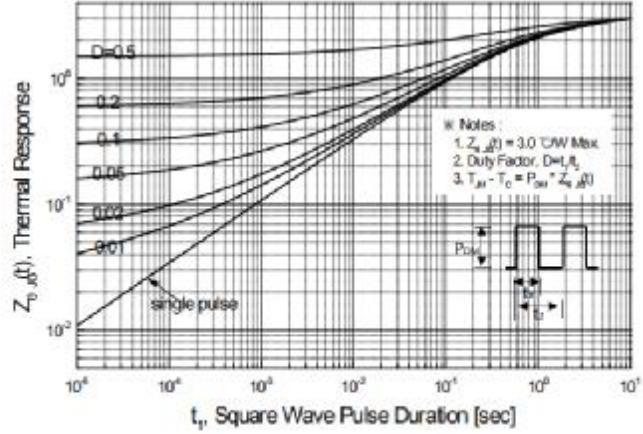
**Figure 9 Maximum Safe Operating Area**



**Figure 10. Maximum Drain Current vs Case Temperature**



**Figure 11-1. Transient Thermal Response Curve for TO-3P/247**



**Figure 11-2. Transient Thermal Response Curve for TO-220F**